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Application/Control No.	Applicant(s)/Patent und Reexamination
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Class	Subclass	Date	Examiner
709	238- 244(Text search)	8/29/2005	нм
370	395.53	8/29/2005	НМ
370	395.554	8/29/2005	нм
370	389-401	8/29/2005	НМ
370	474-475	8/29/2005	нм

INT	INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
DATE EX						
Palm Inventor Search	8/29/2005	НМ				
Searched IEEE	8/29/2005	нм				
Searched EAST DB:USPG-PUB, USPAT, EPO, and JPO	8/29/2005	• НМ				